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(12) United States Design Patent
Shibata et al.

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(45) **Date of Patent: ** Oct. 15, 2013**

(54) **SAMPLE ANALYZER**

(75) Inventors: **Fumie Shibata**, Tokyo (JP); **Shuhei Kaneko**, Hyogo (JP)

(73) Assignee: **Sysmex Corporation**, Kobe (JP)

(**) Term: **14 Years**

(21) Appl. No.: **29/431,327**

(22) Filed: **Sep. 6, 2012**

(51) **LOC (9) Cl.** **24-01**

(52) **U.S. Cl.**
USPC **D24/216**

(58) **Field of Classification Search**
USPC D24/216, 217, 219, 223, 231, 232, 233, D24/107, 169, 186; D10/81; 422/62–65, 67, 422/500, 547; 436/43, 45, 47; 435/287.1, 435/287.3
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D491,272	S	*	6/2004	Alden et al.	D24/216
D549,827	S	*	8/2007	Maeno et al.	D24/169
D657,068	S	*	4/2012	Shibata	D24/216
D670,402	S	*	11/2012	Shibata	D24/216
D682,441	S	*	5/2013	Kim	D24/216

* cited by examiner

Primary Examiner — Anhdao Doan

(74) *Attorney, Agent, or Firm* — Brinks Hofer Gilson & Lione

(57) **CLAIM**

We claim the ornamental design for a sample analyzer, as shown and described.

DESCRIPTION

FIG. **1** is a front perspective view of a sample analyzer of the present invention;
FIG. **2** is a front view thereof;
FIG. **3** is a rear view thereof;
FIG. **4** is a first side view thereof;
FIG. **5** is a second side view thereof;
FIG. **6** is a top view thereof; and,
FIG. **7** is a bottom view thereof.

The broken lines shown represent unclaimed subject matter and form no part of the claimed design. Additionally, the unevenly broken lines in the drawings define the limits of the claimed design.

1 Claim, 4 Drawing Sheets

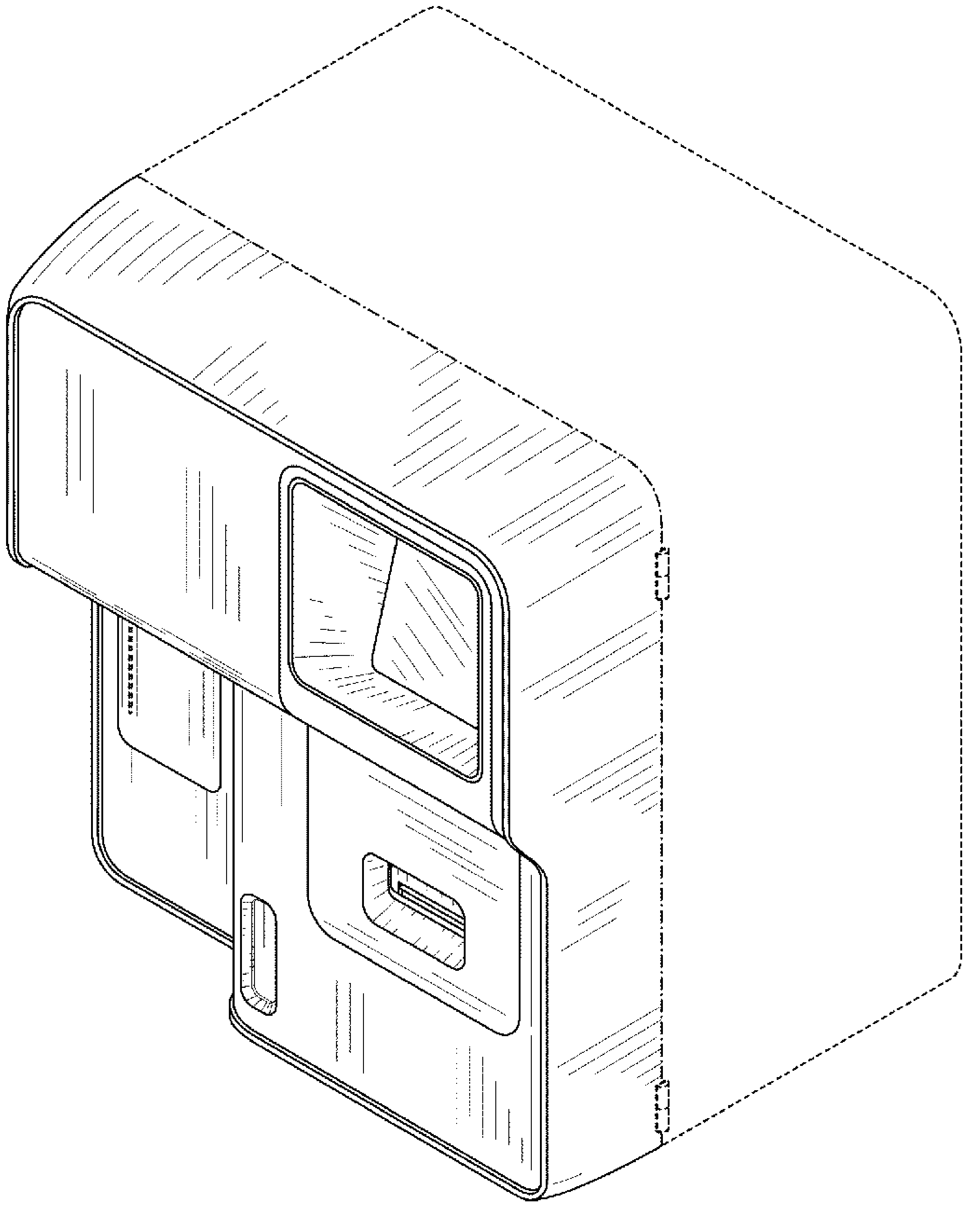

FIG. 1

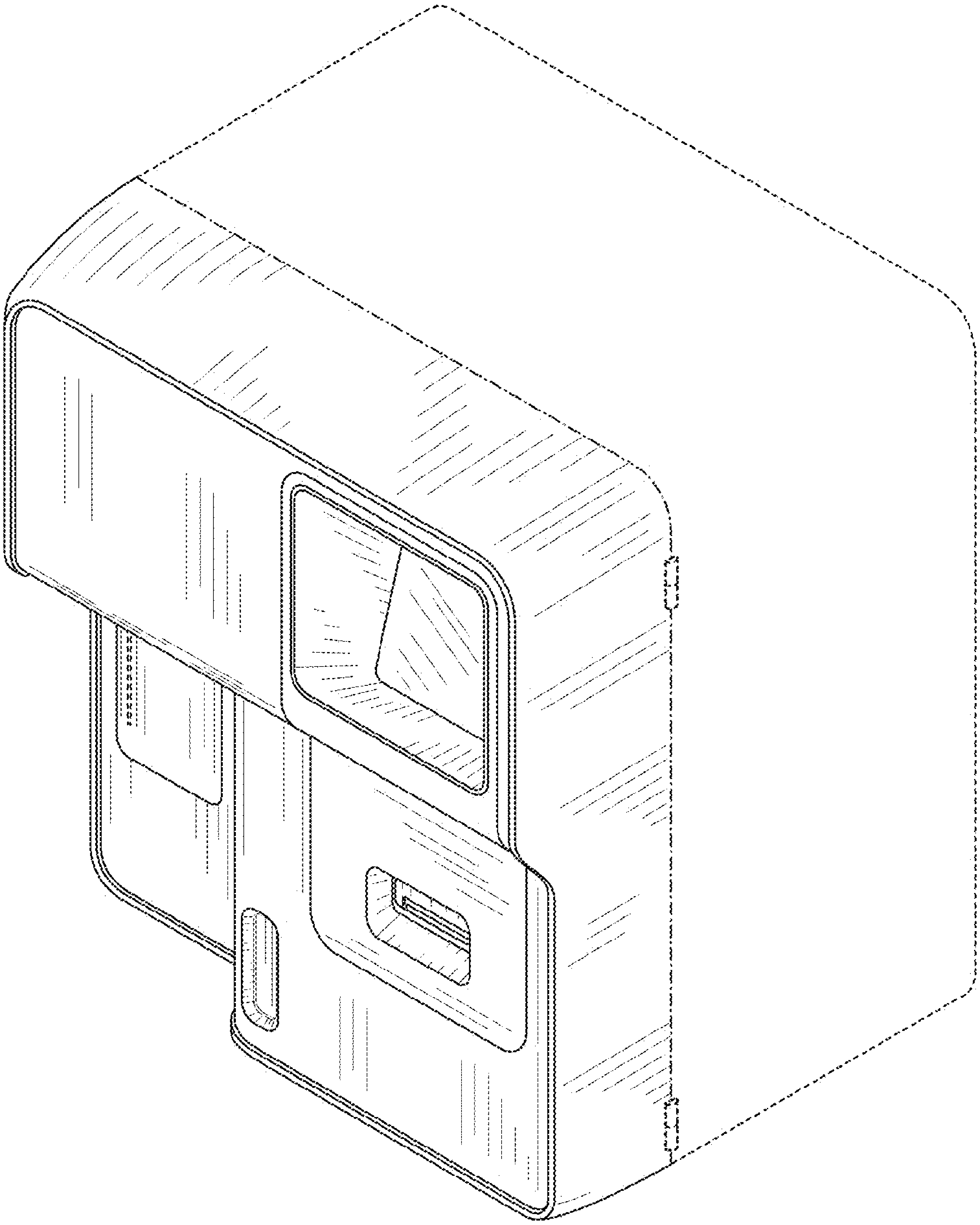

FIG. 2

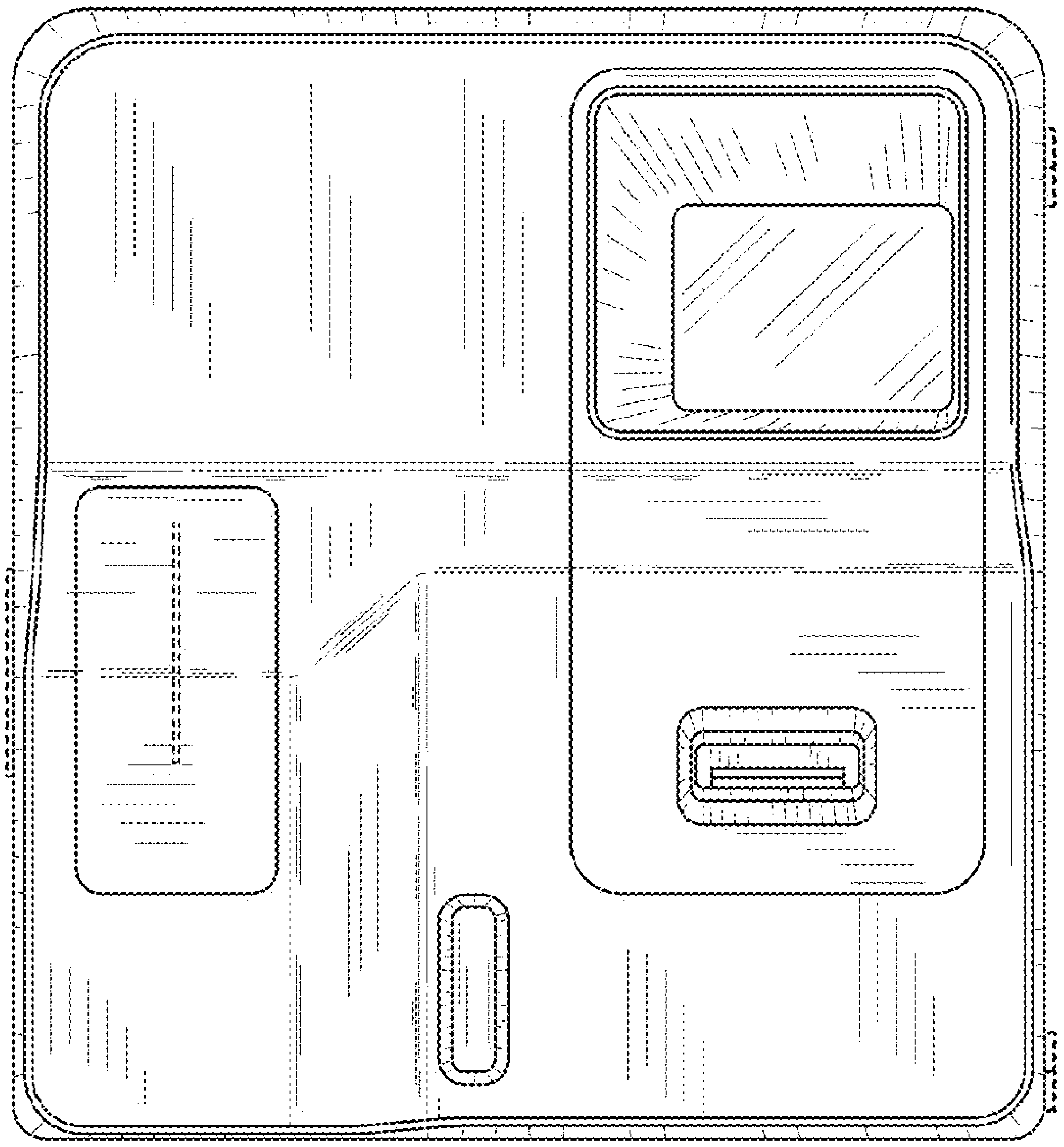

FIG. 3

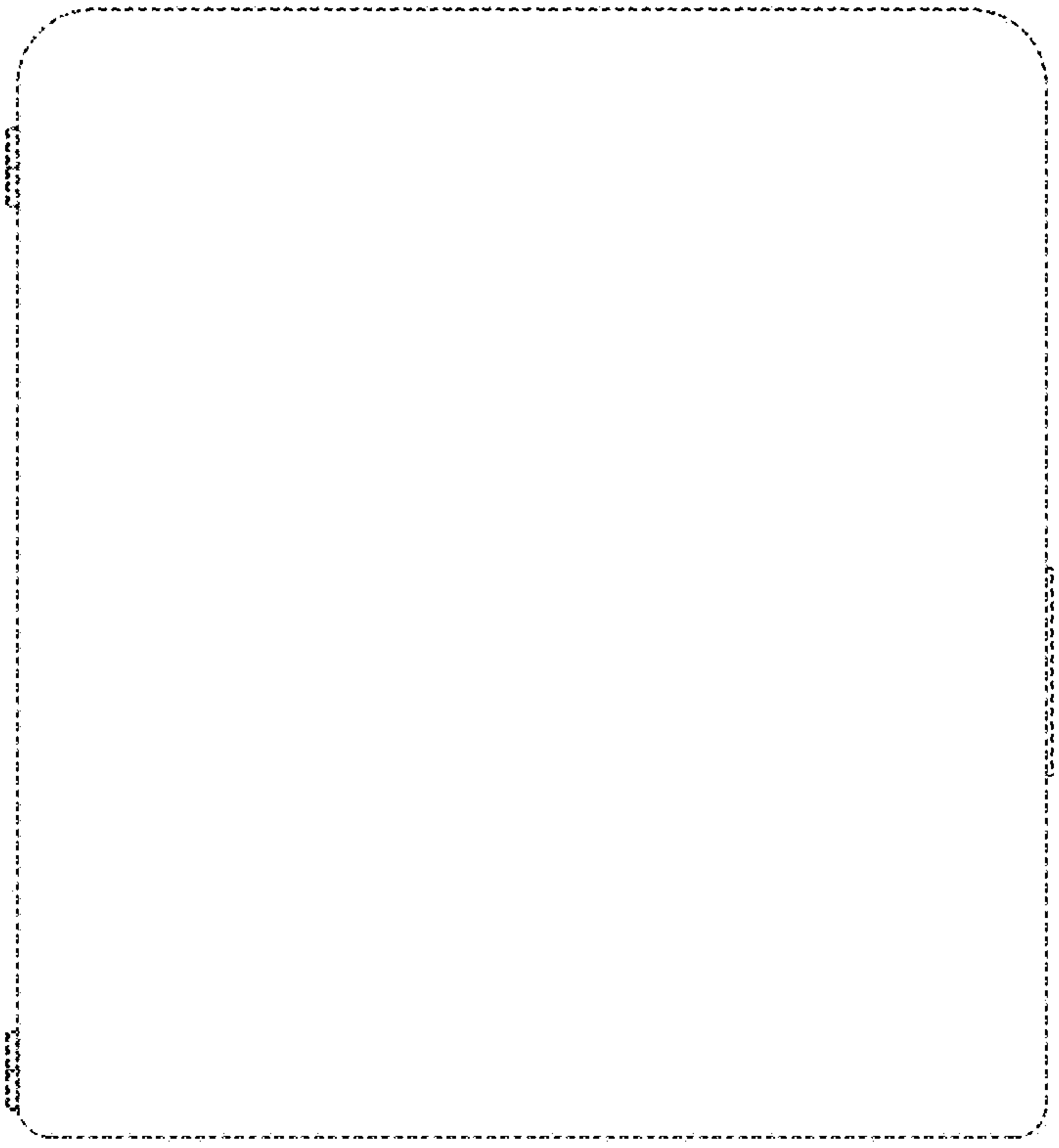

FIG. 4

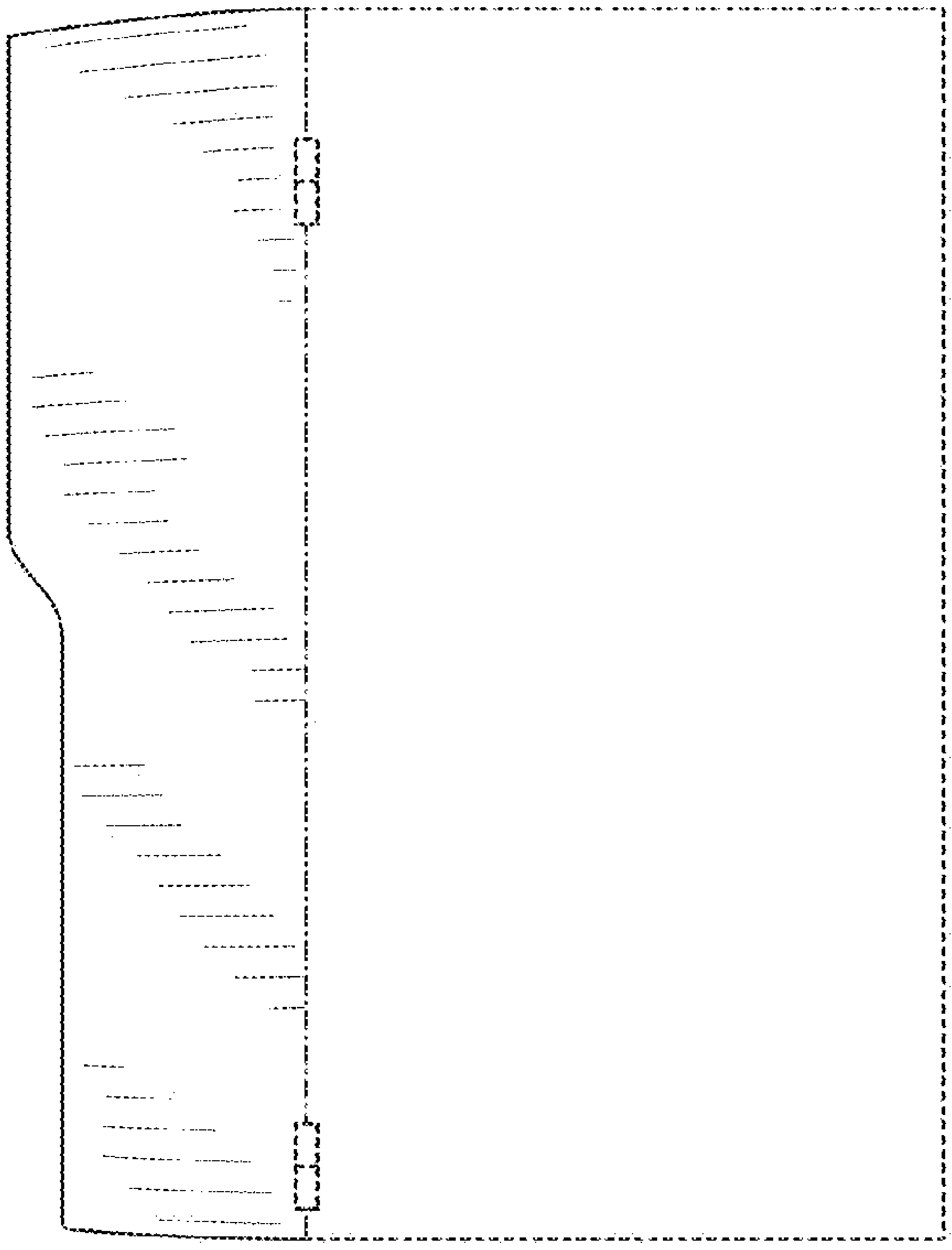

FIG. 5

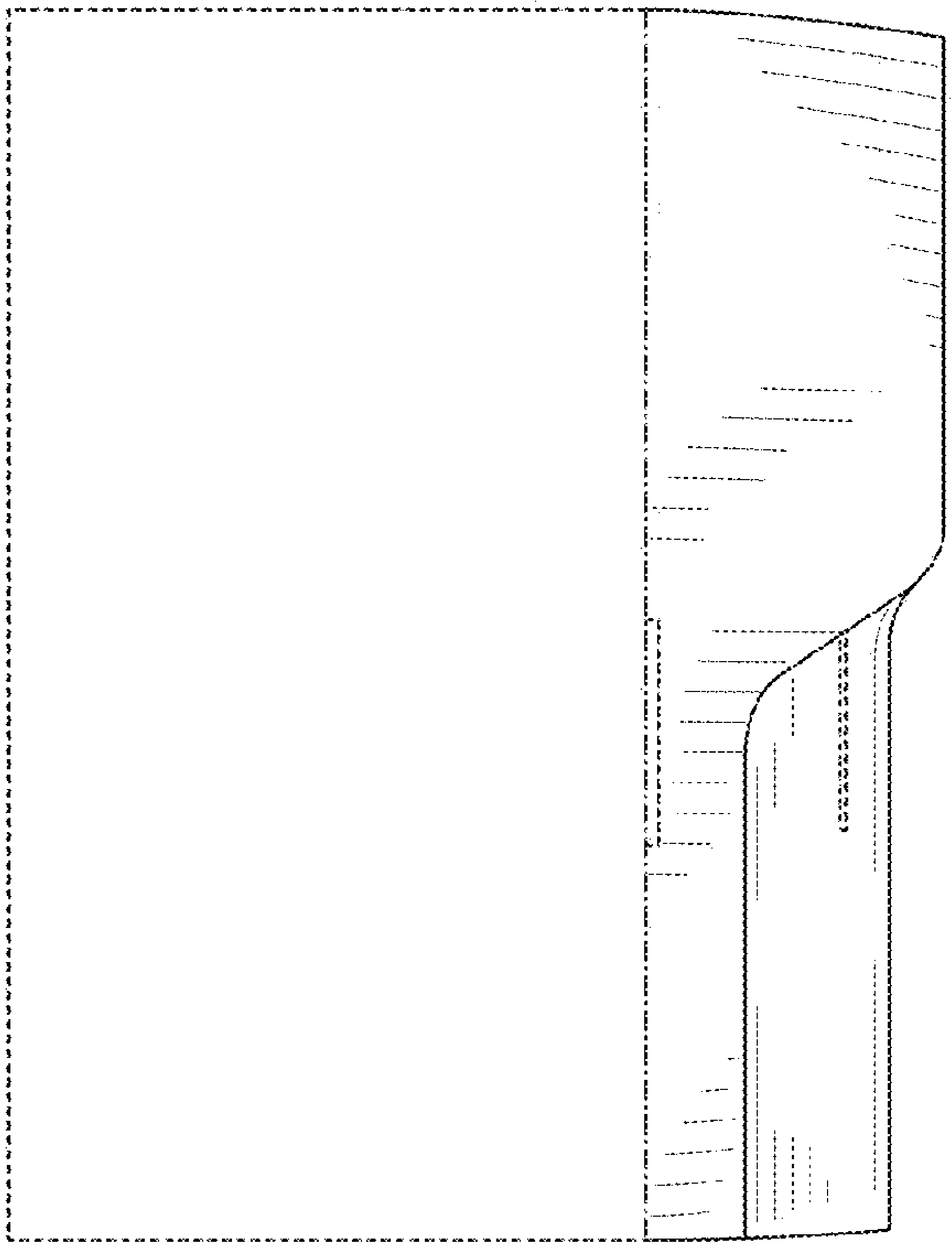

FIG. 6

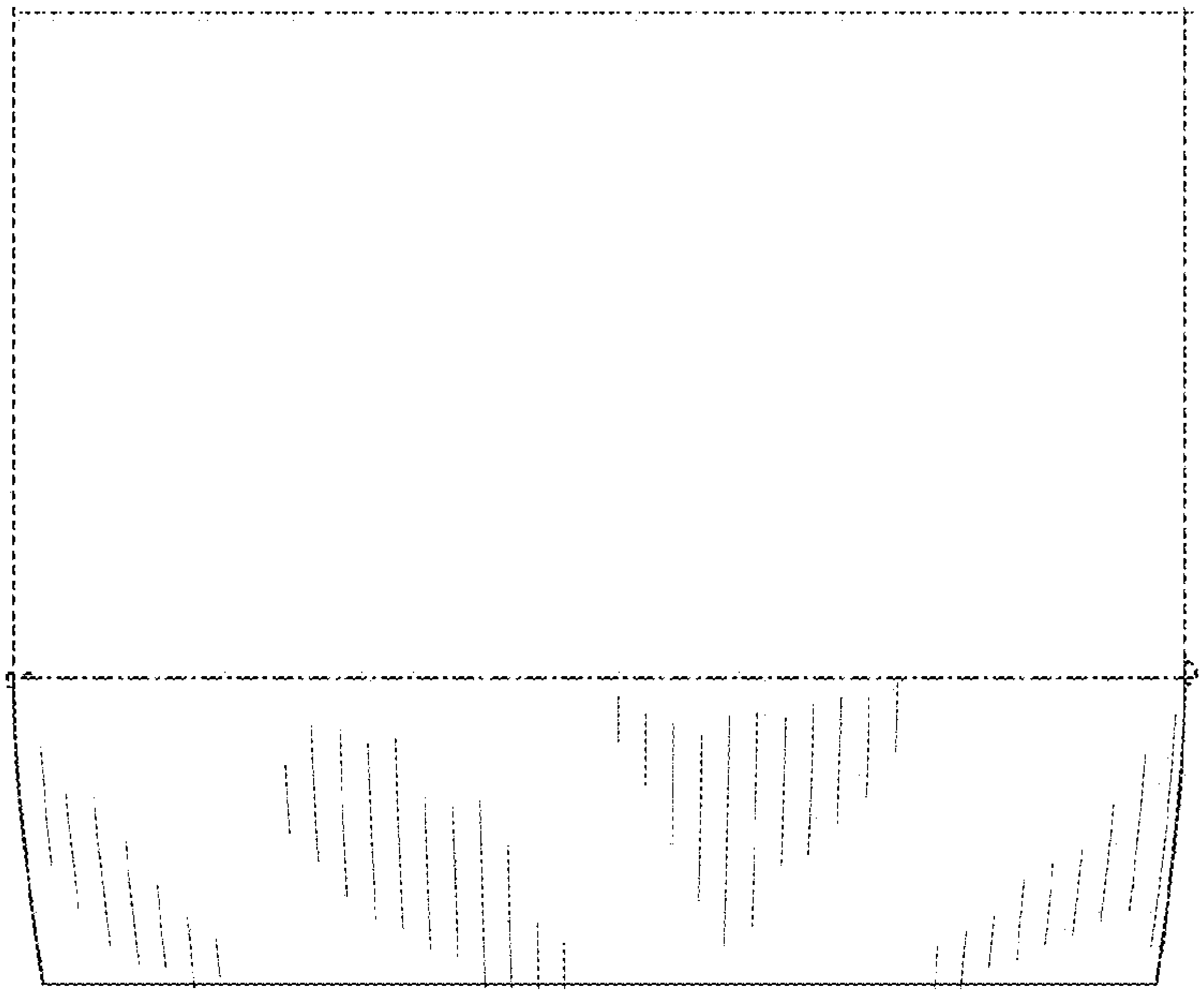

FIG. 7